

# MM1001 LDMOS TRANSISTOR

Document Number: MM1001  
Product Datasheet V4.0

## 10W, 28V High Power RF LDMOS FETs

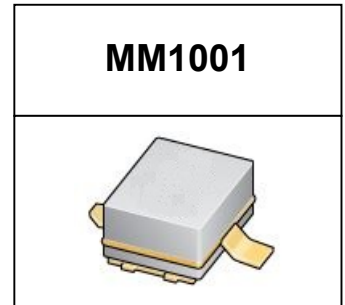
### Description

The MM1001 is a 10-watt, highly rugged, unmatched LDMOS FET, designed for wide-band commercial and industrial applications at frequencies up to 2 GHz. It can be used in Class AB/B and Class C for all typical modulation formats.

- Typical Performance (On Innogration fixture with device soldered):

$V_{DD} = 28$  Volts,  $I_{DQ} = 100$  mA, CW.

Frequency	Gp (dB)	$P_{-1dB}$ (W)	$\eta_D@P_{-1}$ (%)
960 MHz	23	13	63



### Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

### Suitable Applications

- 2-30MHz (HF or Short wave communication)
- 30-88MHz (Ground communication)
- 54-88MHz (TV VHF I)
- 88-108MHz (FM)
- 118 -140MHz (Avionics)
- 136-174MHz (Commercial ground communication)
- 160-230MHz (TV VHF III)
- 30-512MHz (Jammer, Ground/Air communication)
- 470-860MHz (TV UHF)
- 100kHz - 1000MHz (ISM, instrumentation)

**Table 1. Maximum Ratings**

Rating	Symbol	Value	Unit
Drain--Source Voltage	$V_{DSS}$	+95	Vdc
Gate--Source Voltage	$V_{GS}$	-10 to +10	Vdc
Operating Voltage	$V_{DD}$	+40	Vdc
Storage Temperature Range	$T_{stg}$	-65 to +150	°C
Case Operating Temperature	$T_c$	+150	°C
Operating Junction Temperature	$T_j$	+225	°C

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case $T_c = 85^\circ\text{C}$ , $T_j = 200^\circ\text{C}$ , DC test	$R_{\theta JC}$	3	°C/W

**Table 3. ESD Protection Characteristics**

Test Methodology	Class
Human Body Model (per JESD22--A114)	Class 2

**Table 4. Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
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### DC Characteristics

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Drain-Source Voltage $V_{GS}=0, I_{DS}=1.0mA$	$V_{(BR)DSS}$	90	97		V
Zero Gate Voltage Drain Leakage Current $(V_{DS} = 75V, V_{GS} = 0 V)$	$I_{DSS}$	—	—	1	$\mu A$
Zero Gate Voltage Drain Leakage Current $(V_{DS} = 28 V, V_{GS} = 0 V)$	$I_{DSS}$	—	—	1	$\mu A$
Gate--Source Leakage Current $(V_{GS} = 10 V, V_{DS} = 0 V)$	$I_{GSS}$	—	—	1	$\mu A$
Gate Threshold Voltage $(V_{DS} = 28V, I_D = 50 \mu A)$	$V_{GS(th)}$	—	2.07	—	V
Gate Quiescent Voltage $(V_{DD} = 28 V, I_D = 100 mA, \text{Measured in Functional Test})$	$V_{GS(Q)}$	—	3.3	—	V
Common Source Input Capacitance $(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	$C_{ISS}$		16.2		pF
Common Source Output Capacitance $(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	$C_{OSS}$		5.9		pF
Common Source Feedback Capacitance $(V_{GS} = 0V, V_{DS} = 28 V, f = 1 MHz)$	$C_{RSS}$		0.5		pF

**Functional Tests** (In Demo Test Fixture, 50 ohm system)  $V_{DD} = 28 Vdc, I_{DQ} = 100mA, f = 960 MHz, CW$  Signal Measurements.

Power Gain	$G_p$	—	23	—	dB
Drain Efficiency@P1dB	$\eta_D$	—	63	—	%
1 dB Compression Point	$P_{-1dB}$	—	13	—	W
Input Return Loss	IRL	—	-7	—	dB

**Load Mismatch (In Innogration Test Fixture, 50 ohm system):**  $V_{DD} = 28 Vdc, I_{DQ} = 100 mA, f = 960 MHz$

VSWR 20:1 at 13W pulse CW Output Power	No Device Degradation
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## TYPICAL CHARACTERISTICS

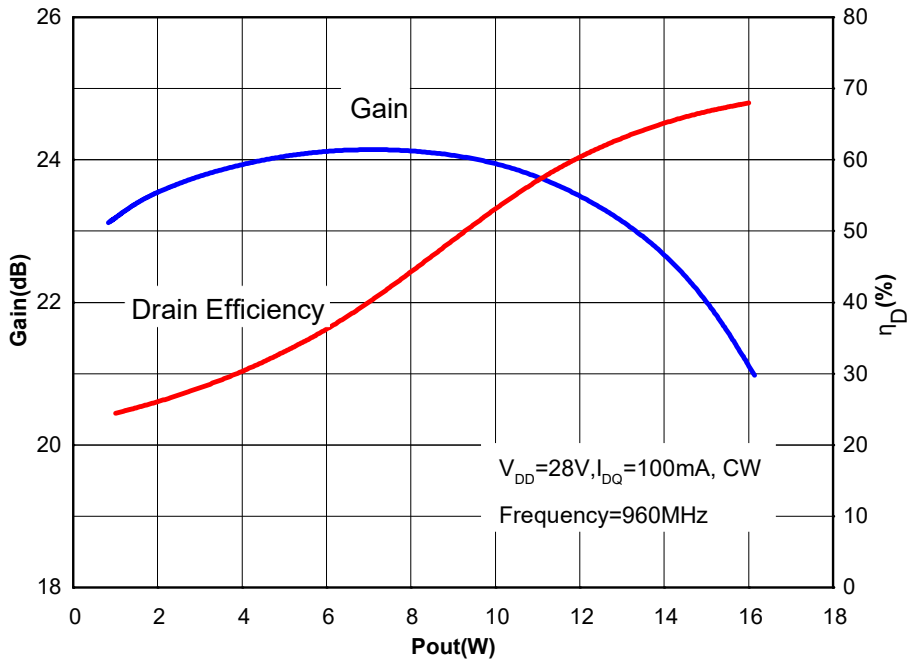


Figure 1. Power gain and drain efficiency as function of Power out

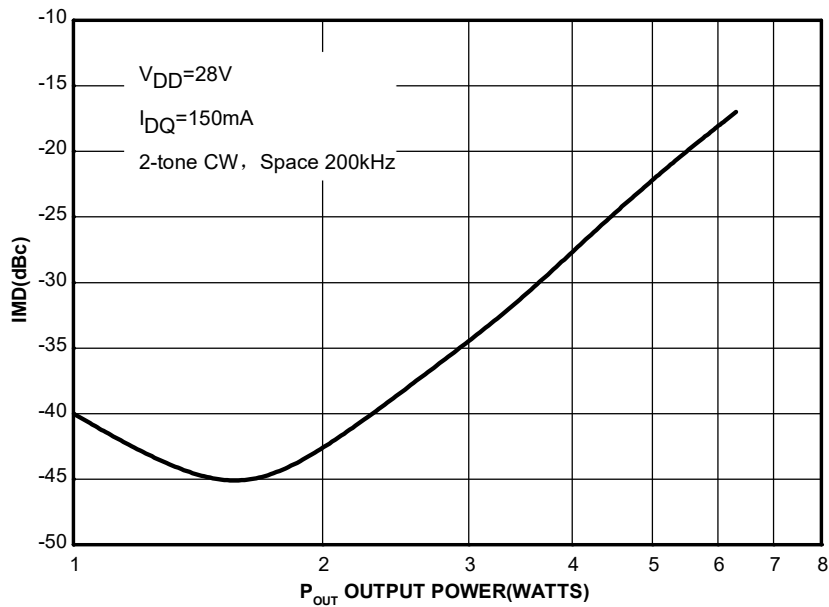


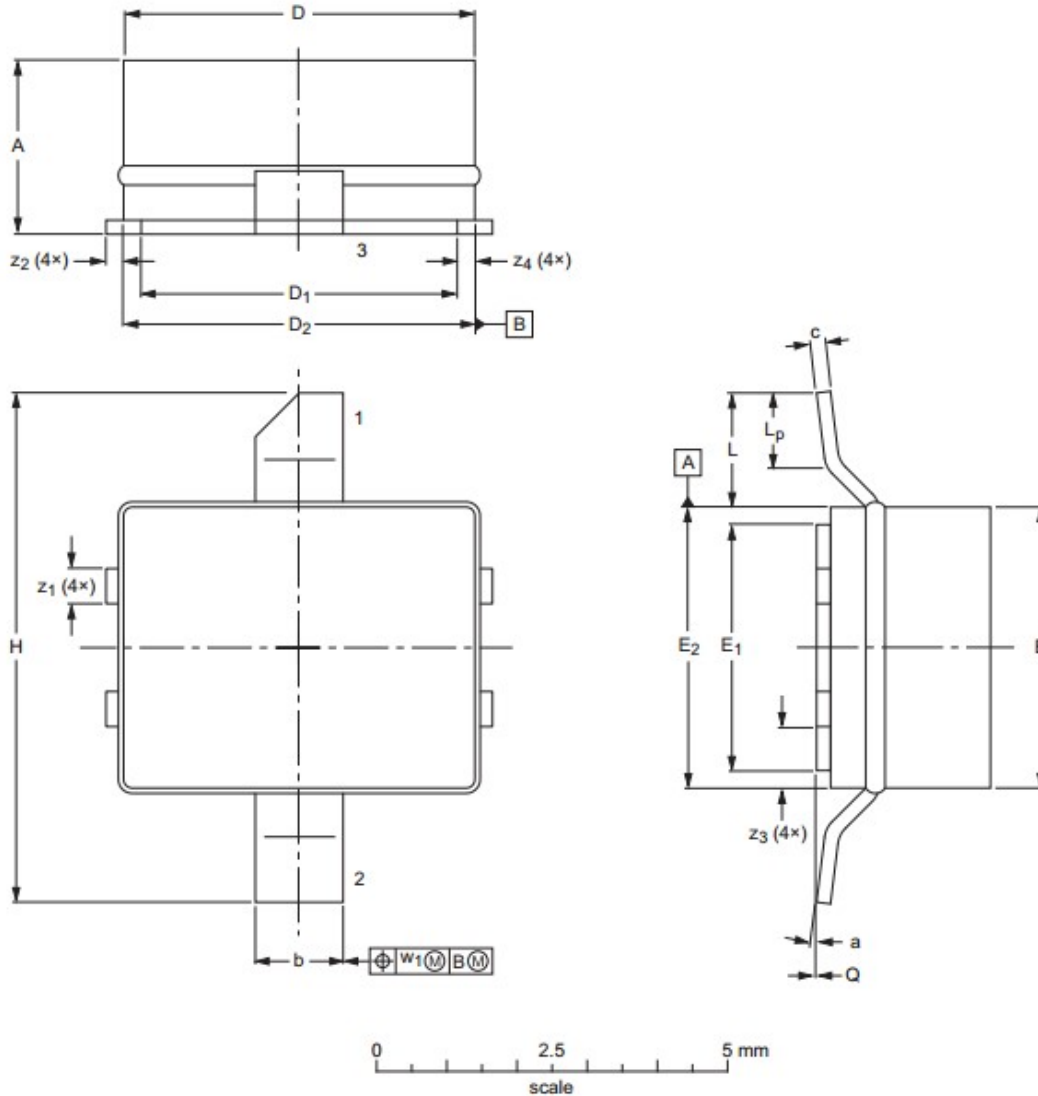
Figure 2. IMD3 versus Output Power

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## Package Outline

Earless Flanged ceramic package; 2 leads(1-Drain,2-Gate,3-Source)



UNIT	A	b	c	D	D <sub>1</sub>	E	E <sub>1</sub>	E <sub>2</sub>	H	L	L <sub>p</sub>	Q	w <sub>1</sub>	z <sub>1</sub>	z <sub>2</sub>	z <sub>3</sub>	z <sub>4</sub>	α
mm	2.34	1.35	0.23	5.16	4.65	4.14	3.63	4.14	7.49	2.03	1.02	0.1	0.25	0.58	0.25	0.97	0.51	7°
	2.13	1.19	0.18	5.00	4.50	3.99	3.48	3.99	7.24	1.27	0.51	0.0		0.43	0.18	0.81	0.00	0°

OUTLINE VERSION	REFERENCE			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
PKG-MM					18/6/2014

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## Revision history

Table 5. Document revision history

Date	Revision	Datasheet Status
2015/4/29	Rev 1.0	Preliminary Datasheet
2016/8/8	Rev 2.0	Preliminary Datasheet
2016/11/23	Rev 3.0	Preliminary Datasheet
		Add test data and graph
2016/12/27	Rev 3.1	Preliminary Datasheet
		Add Thermal Resistance
2017/02/22	Rev 4.0	Product Datasheet
		Add CV parameter

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